

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs		User Part Number						
		PIMP31PA Part Description						
								Nexperia DHAM Small Signal Bipolar Transistor
		MCD package						
		Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects
	<b>TEST</b> Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
# 2	<b>PC</b> Preconditioning	JESD22-A113 Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85% Reflow soldering	24 hours 168 hours 3 cycles	464	20960	0		
# 5	HTRB High Temperature Reverse Bias	MIL-STD-750-1 M1039 Method A Tj = Tjmax, Vr = 100% of max. datasheet reverse voltage	1000 hours	415	18680	0		
# 7	<b>TC</b> Temperature Cycling	JESD22-A104 -65 °C to Tjmax, not to exceed 150°C	500 cycles	116	5240	0		
# 8 <b>or</b>	<b>UHAST</b> Unbiased HAST	JESD22-A118 Tamb = 130 °C, RH = 85 %	— 96 hours	116	5240	0		
# 8a	<b>AC</b> Autoclave	JESD22-A102 Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)						
# 9	<b>H3TRB</b> High Humidity High Temperature Reverse Bias	JESD22-A101 Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage <sup>[1]</sup>	1000 hours	116	5240	0		
# 10	IOL Intermittent Operating Life	MIL-STD-750 Method 1037 ton = toff, devices powered to insure $\Delta Tj = 100  ^{\circ} C$	333 hours	116	5240	0		
# 20	<b>RSH</b> Resistance to Solder Heat	JESD22-A111 260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.		
# 21	<b>SD</b> Solderability	J-STD-002		86	2580	0		

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia	Small Signal Bipolar				
DHAM	Transistor	18680	0	0,23	4,40E+09

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